INTEGRATED CIRCUITS



Product specification Supersedes data of 1998 Feb 25 IC23 Data Handbook

1998 Oct 07



Philips Semiconductors

UNIT

ns pF pF μA

mΑ

10

16-bit buffer/line driver (3-State)

74ABT16244A 74ABTH16244A

FEATURES

- 16-bit bus interface
- Multiple V_{CC} and GND pins minimize switching noise
- Power-up 3-State
- 3-State buffers
- Output capability: +64 mA/–32mA
- Live insertion/extraction permitted

QUICK REFERENCE DATA

- Latch-up protection exceeds 500mA per JEDEC Std 17
- ESD protection exceeds 2000 V per MIL STD 883 Method 3015 and 200 V per Machine Model
- 74ABTH16244A incorporates bus hold data inputs which eliminate the need for external pull up resistors to hold unused inputs
- Bus-hold data inputs eliminate the need for external pull-up resistors to hold unused inputs

DESCRIPTION

The 74ABT16244A high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT16244A device is a 16-bit buffer that is ideal for driving bus lines. The device features four Output Enables ($1\overline{OE}$, $2\overline{OE}$, $3\overline{OE}$, $4\overline{OE}$), each controlling four of the 3-State outputs. Two options are available, 74ABT16244A which does not have the bus hold feature and 74ABTH16244A which incorporates the bus hold feature.

SYMBOL	PARAMETER	CONDITIONS T _{amb} = 25°C; GND = 0V	TYPICAL
t _{PLH} t _{PHL}	Propagation delay nAx to nYx	$C_L = 50 pF; V_{CC} = 5V$	1.7 2.1
C _{IN}	Input capacitance	$V_{I} = 0V \text{ or } V_{CC}$	4
C _{OUT}	Output capacitance	$V_{O} = 0V \text{ or } V_{CC}; 3-State$	7
I _{CCZ}	Quiescent supply current	Outputs disabled; $V_{CC} = 5.5V$	450
		$O_{\rm cutra utra lawa }) (\Gamma \Gamma) ($	40

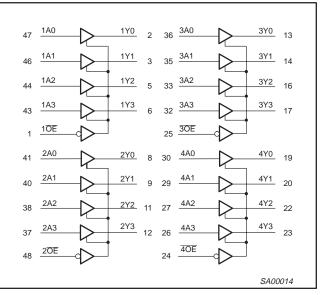
ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
48-Pin Plastic SSOP Type III	–40°C to +85°C	74ABT16244A DL	BT16244A DL	SOT370-1
48-Pin Plastic TSSOP Type II	–40°C to +85°C	74ABT16244A DGG	BT16244A DGG	SOT362-1
48-Pin Plastic SSOP Type III	–40°C to +85°C	74ABH16244A DL	BH16244A DL	SOT370-1
48-Pin Plastic TSSOP Type II	-40°C to +85°C	74ABH16244A DGG	BH16244A DGG	SOT362-1

Outputs low; V_{CC} = 5.5V

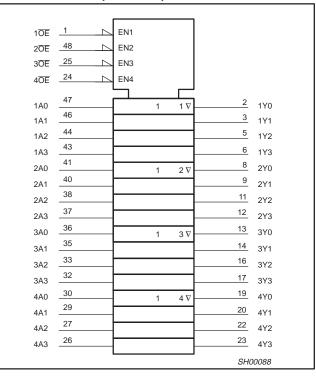
LOGIC SYMBOL

ICCL



74ABT16244A 74ABTH16244A

LOGIC SYMBOL (IEEE/IEC)



PIN CONFIGURATION

10E		48 20E
1Y0	2	47 1A0
1Y1	3	46 1A1
GND	4	45 GND
1Y2	5	44 1A2
1Y3	6	43 1A3
Vcc	7	42 V _{CC}
2Y0	8	41 2A0
2Y1	9	40 2A1
GND	10	39 GND
2Y2	11	38 2A2
2Y3	12	37 2A3
3Y0	13	36 3A0
3Y1	14	35 3A1
GND	15	34 GND
3Y2	16	33 3A2
3Y4	17	32 3A3
Vcc	18	31 V _{CC}
4Y0	19	30 4A0
4Y1	20	29 4A1
GND	21	28 GND
4Y2	22	27 4A2
4Y3	23	26 4A3
40E	24	25 3OE
	L	
		5700013

PIN DESCRIPTION

PIN NUMBER	SYMBOL	NAME AND FUNCTION
47, 46, 44, 43 41, 40, 38, 37 36, 35, 33, 32 30, 29, 27, 26	1A0 – 1A3, 2A0 – 2A3, 3A0 – 3A3, 4A0 – 4A3	Data inputs
2, 3, 5, 6 8, 9, 11, 12 13, 14, 16, 17 19, 20, 22, 23	1Y0 – 1Y3, 2Y0 – 2Y3, 3Y0 – 3Y3, 4Y0 – 4Y3	Data outputs
1, 48 25, 24	1 <u>0E</u> , 2 <u>0E</u> , 30E, 40E	Output enables
4, 10, 15, 21 28, 34, 39, 45	GND	Ground (0V)
7, 18, 31, 42	V _{CC}	Positive supply voltage

FUNCTION TABLE

INP	INPUTS			
nOE	nAx	nYx		
L	L	L		
L	Н	Н		
н	Х	Z		

H = High voltage level

L = Low voltage level

X = Don't care Z = High impedance "off" state

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ABSOLUTE MAXIMUM RATINGS^{1, 2}

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V _{CC}	DC supply voltage		-0.5 to +7.0	V
Ι _{ΙΚ}	DC input diode current	V ₁ < 0	-18	mA
VI	DC input voltage ³		-1.2 to +7.0	V
I _{OK}	DC output diode current	V _O < 0	-50	mA
V _{OUT}	DC output voltage ³	output in Off or High state	-0.5 to +5.5	V
	DC sutput surrent	output in Low state	128	
IOUT	DC output current	output in High state	-64	mA
T _{stg}	Storage temperature range		-65 to 150	°C

NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

2. The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.

The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIM	UNIT	
STMBOL	FARAMETER		MAX	UNIT
V _{CC}	DC supply voltage	4.5	5.5	V
VI	Input voltage	0	V _{CC}	V
V _{IH}	High-level input voltage	2.0		V
V _{IL}	Low-level input voltage		0.8	V
I _{OH}	High-level output current		-32	mA
I _{OL}	Low-level output current		64	mA
Δt/Δv	Input transition rise or fall rate	0	10	ns/V
T _{amb}	Operating free-air temperature range	-40	+85	°C

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DC ELECTRICAL CHARACTERISTICS

						LIMITS			
SYMBOL	PARAMETER	TEST CO	NDITIONS	Tai	_{mb} = +25	S°C	T _{amb} = −40°C to +85°C		UNIT
			F		Тур	Max	Min	Мах	
VIK	Input clamp voltage	$V_{CC} = 4.5V; I_{IK} = -18m$	A		-0.9	-1.2		-1.2	V
		V _{CC} = 4.5V; I _{OH} = -3m	A; $V_I = V_{IL}$ or V_{IH}	2.5	2.9		2.5		
V _{OH}	High-level output voltage	$V_{CC} = 5.0V; I_{OH} = -3m$	A; $V_I = V_{IL}$ or V_{IH}	3.0	3.4		3.0		V
		$V_{CC} = 4.5 V; I_{OH} = -32 r$	mA; V _I = V _{IL} or V _{IH}	2.0	2.4		2.0		
V _{OL}	Low-level output voltage	$V_{CC} = 4.5 V; I_{OL} = 64 m.$	A; $V_I = V_{IL}$ or V_{IH}		0.42	0.55		0.55	V
l	Input leakage current	$V_{CC} = 5.5V; V_I = GND$	or 5.5V		±0.01	±1.0		±1.0	μΑ
	Input leakage current	$V_{CC} = 5.5V; V_I = V_{CC}$ or GND	Control pins		±0.01	±1		±1	
I _I	74ABTH16244A	$V_{CC} = 5.5V; V_{I} = V_{CC}$	Data Pins		0.01	1		1	μA
		$V_{CC} = 5.5V; V_{I} = 0$	Data Filis		-2	-3		-5	1
		$V_{CC} = 4.5V; V_{I} = 0.8V$ $V_{CC} = 4.5V; V_{I} = 2.0V$		50			50		μA
I _{HOLD}	Bus Hold current A inputs ⁴ 74ABTH16244A			-75			-75		
		$V_{CC} = 5.5V; V_I = 0 \text{ to } 5.5V$		±500					
I _{OFF}	Power-off leakage current	V_{CC} = 0.0V; V_{O} or V_{I} \leq	4.5V		±5.0	±100		±100	μA
I _{PU} /I _{PD}	Power-up/down 3-State output current	$\begin{array}{l} V_{\underline{CC}} = 2.0 \text{V}; \ \text{V}_{\underline{O}} = 0.5 \text{V} \\ \text{V}_{\underline{OE}} = \text{V}_{\underline{CC}} \end{array}$; $V_I = GND \text{ or } V_{CC}$;		±5.0	±50		±50	μΑ
I _{OZH}	3-State output High current	$V_{CC} = 5.5 V; V_{O} = 5.5 V$; $V_{I} = V_{IL}$ or V_{IH}		0.1	10		10	μA
I _{OZL}	3-State output Low current	$V_{CC} = 5.5 V; V_{O} = 0.0 V$; $V_{I} = V_{IL} \text{ or } V_{IH}$		-0.1	-10		-10	μA
I _{CEX}	Output High leakage current	V _{CC} = 5.5V; V _O = 5.5V	; $V_I = GND \text{ or } V_{CC}$		5.0	50		50	μA
Ι _Ο	Output current ¹	V _{CC} = 5.5V; V _O = 2.5V		-50	-100	-180	-50	-180	mA
I _{CCH}		V _{CC} = 5.5V; Outputs Hi	gh, $V_I = GND$ or V_{CC}		0.45	1.0		1.0	mA
I _{CCL}	Quiescent supply current ³	V_{CC} = 5.5V; Outputs Lo	ow, $V_I = GND$ or V_{CC}		10	19		19	mA
I _{CCZ}		$V_{CC} = 5.5V$; Outputs 3- V _I = GND or V _{CC}	State;		0.45	1.0		1.0	μA
		Outputs enabled, one data input at 3.4V, other inputs at V _{CC} or GND; V _{CC} = $5.5V$			100	250		250	
ΔI_{CC}	Additional supply current per input pin ^{2, 3}	Outputs disabled, one data input at 3.4V, other inputs at V_{CC} or GND; $V_{CC} = 5.5V$			100	250		250	μA
		Control pins, outputs d input at 3.4V, other input $V_{CC} = 5.5V$	isabled, one enable uts at V_{CC} or GND;		100	250		250	

NOTES:

1. Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

This is the increase in supply current for each input at 3.4V.
This data sheet limit may vary among suppliers.
This is the bus hold overdrive current required to force the input to the opposite logic state.

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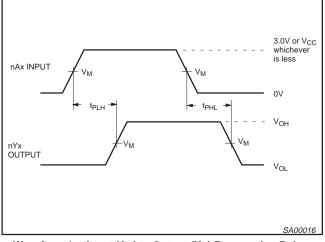
AC CHARACTERISTICS

GND = 0V; $t_R = t_F = 2.5 \text{ns}$; $C_L = 50 \text{pF}$, $R_L = 500 \Omega$

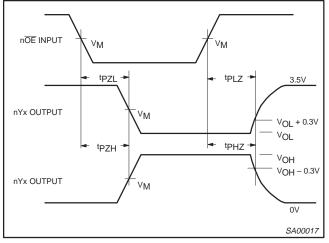
					LIMITS			
SYMBOL	PARAMETER	WAVEFORM	T V	_{amb} = +25°0 √ _{CC} = +5.0V		$T_{amb} = -40^{\circ}$ $V_{CC} = +5.$	°C to +85°C .0V ±0.5V	UNIT
			MIN	TYP	MAX	MIN	MAX	
t _{PLH} t _{PHL}	Propagation delay nAx to nYx	1	1.1 1.3	1.7 2.1	2.6 2.9	1.1 1.3	2.8 3.4	ns
t _{PZH} t _{PZL}	Output enable time to High and Low level	2	1.6 2.3	2.7 3.5	3.7 4.0	1.6 2.3	4.5 4.8	ns
t _{PHZ} t _{PLZ}	Output disable time from High and Low level	2	2.0 1.6	3.0 2.4	4.0 3.2	2.0 1.6	4.6 4.1	ns

AC WAVEFORMS

 V_{M} = 1.5V, V_{IN} = GND to 3.0V



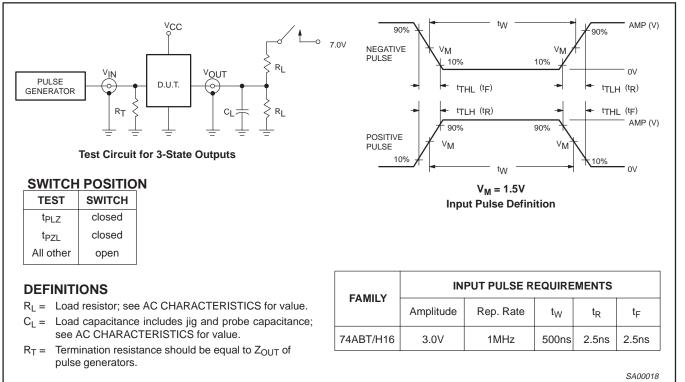
Waveform 1. Input (An) to Output (Yn) Propagation Delays



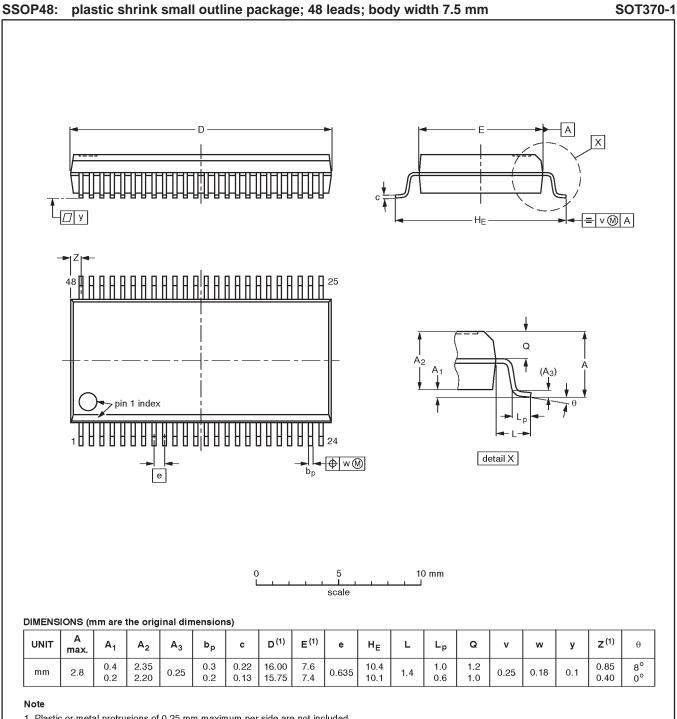
Waveform 2. 3-State Output Enable and Disable Times

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TEST CIRCUIT AND WAVEFORMS



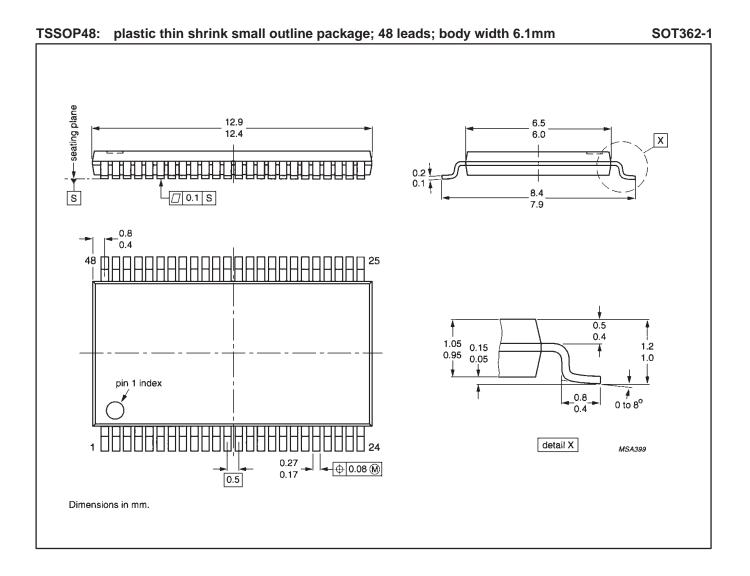
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1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	RENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT370-1		MO-118AA			$\bigcirc \bigcirc$	93-11-02 95-02-04

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Data sheet status

Data sheet status	Product status	Definition ^[1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
Product specification	Production	This data sheet contains final specifications. Philips Semiconductors reserves the right to make changes at any time without notice in order to improve design and supply the best possible product.

[1] Please consult the most recently issued datasheet before initiating or completing a design.

Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition - Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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